



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent

Applicant(s): Keiji YADA, et al.) Re: Information Disclosure
Serial No.: 10/719,008) Statement
Filed: November 21, 2003) Group: not yet assigned
For: "X-RAY MICROSCOPIC INSPECTION) Examiner: not yet assigned
APPARATUS") Our Ref: B-5309 621525-5
) Date: September 1, 2004

Commissioner for Patents
P.O. Box 1450
Alexandria VA, 22313-1450

Sir:

In accordance with the Applicants' duty to disclose information which may be material to the examination of this application, the undersigned respectfully requests that the Examiner consider on the merits the documents listed on the enclosed Form PTO-1449 (modified) before issuing the first Office Action on the merits. We are enclosing herewith a copy of each document listed on the enclosed Form PTO-1449 (modified) .

It should be noted that the above-identified application may be related by subject matter to the following U.S. Application(s): 10/719,887, filed November 21, 2003. Pursuant to 37 C.F.R. 1.56(a) and M.P.E.P. 2004, paragraph 9, the applicant brings these co-pending applications to the attention of the Examiner. The Examiner should consider this information during the prosecution of the above-identified application. However, citation of these applications does not constitute an admission that the claims of the present application are substantially similar or similar to those of the applications listed above.

Japanese Document No. 2004-138460 is not in English. A concise English-language explanation of the relevance of Japanese Document No. 2004-138460 can be found in the enclosed English-language

Information Disclosure Statement
USSN 10/719,008
September 1, 2004
Page 2

abstract and partial translation.

The document by Keiji Yada, et al., entitled "Development of Projection X-Ray Microscopy and Its Biological Applications," is not in English. A concise English-language explanation of the relevance of the document by Keiji Yada, et al., entitled "Development of Projection X-Ray Microscopy and Its Biological Applications," can be found in the enclosed English-language reference description.

The document by Keiji Yada, et al., entitled "Development of Soft X-Ray Microscopy," is not in English. A concise English-language explanation of the relevance of the document by Keiji Yada, et al., entitled "Development of Soft X-Ray Microscopy," can be found in the enclosed English-language reference description.

The document by Keiji Yada, et al., entitled "Projection X-Ray Shadow Microscopy Using SEM," is not in English. A concise English-language explanation of the relevance of the document by Keiji Yada, et al., entitled "Projection X-Ray Shadow Microscopy Using SEM," can be found in the enclosed English-language reference description.

The filing of this Information Disclosure Statement (IDS) shall not be construed as a representation that a search has been made (37 C.F.R. 1.97(g)), an admission that the information cited is, or is considered to be, material to patentability, or that no other material information exists.

The Applicants believe that this IDS is being submitted before the issuance of a first Office Action on the merits and before the issuance of a Final Rejection or Notice of Allowance. Therefore,

Information Disclosure Statement
USSN 10/719,008
September 1, 2004
Page 3

no official fees should be due; and this IDS should be considered on the merits. If this IDS is being submitted after the issuance of the first Office Action on the merits and before the issuance of a Final Rejection or Notice of Allowance, please contact the undersigned to authorize a payment of \$180.00 (or any other required amount), which is the fee set forth in 37 C.F.R. § 1.97(c), if the Examiner believes that such a fee is due in order for this IDS to be considered on the merits.

The filing of this Information Disclosure Statement shall not be construed as an admission against interest in any manner. (Notice of January 9, 1992, 1135 O.G. 13-25, at 25.)

The person making this statement is the practitioner who signs below on the basis of information supplied by an individual associated with the filing and prosecution of this application (37 C.F.R. § 1.56(c)) and on the basis of information in the practitioner's file.

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first-class mail in an envelope addressed to the "Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450", on September 1, 2004 by Shana Morda.



Respectfully submitted,



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Enclosures: Form PTO-1449 (modified) (1 page)
Copy of documents listed on Form PTO-1449 (modified)



Information Disclosure Statement
SN 10/719,008
September 1, 2004
Page 4

Form PTO-1449 (Modified)	ATTY DOCKET NO. B-5309 621525-5	U.S. SERIAL NO. 10/719,008
LIST OF PATENTS AND PUBLICATIONS STATEMENT	APPLICANTS Keiji YADA, et al.	
	FILING DATE November 21, 2003	GROUP not yet assigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	ISSUE DATE	NAME	CLASS	SUB-CLASS	FILING DATE or 102(e) DATE IF APPROPRIATE
	10/719,887		Yada et al.			11/21/2003

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO
	2004-138460	5/2004	JP			Abstract and partial translation

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	Nixon, W.C., "High-Resolution X-Ray Projection Microscopy," <i>Proc. Roy. Soc.</i> , A232, pp. 475-485 (1960).
	Yada, K., et al., "Development of Projection X-Ray Microscopy and Its Biological Applications," <i>Bulletin of Aomori Public College</i> , Vol. 1, pp. 2-13 (1996).
	Yada, K., et al., "Development of Soft X-Ray Microscopy," <i>Biophysics</i> , Vol. 33, No. 4, pp. 8-16 (1980).
	Yada, K., et al., "High-Resolution Projection X-Ray Microscopy," <i>Multidimensional Microscopy</i> , Chapter 8, pp. 133-150 (1994).
	Yada, K., et al., "Projection X-Ray Shadow Microscopy Using SEM," <i>Bulletin of the Research Institute for Scientific Measurements</i> , Tohoku University, Vol. 29, No. 1, pp. 25-42 (1980).

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.